



RF Exposure Report

Test report
On Behalf of
Orient Link Limited
For
Wireless Charger

Model No.: 5502267(SW0042-BK), 5502269(SW0042-WE)

FCC ID: 2AIMJ-SW0042

IC: 21538-SW0042

Prepared for: Orient Link Limited

9/F, 1063 King's Road, Quarry Bay, Hong Kong, China

Prepared By: Shenzhen HUAK Testing Technology Co., Ltd.

1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao'an District, Shenzhen, Guangdong,

China

Date of Test: Jan. 08, 2019 to Jan. 15, 2019

Date of Report: Jan. 15, 2019
Report Number: HK1901140090E



TEST RESULT CERTIFICATION

Applicant's name	Orient Link Limited
Address:	9/F, 1063 King's Road, Quarry Bay, Hong Kong, China
Manufacture's Name:	Sweda (Shen Zhen) Electronics Company Limited
Address:	Block C, Lian Tang Chun Wei Ind. Bldg., Lian Tang, ShenZhen, PRC. Postal Code=518004
Factory's Name:	Sweda (Shen Zhen) Electronics Company Limited
Address:	Block C, Lian Tang Chun Wei Ind. Bldg., Lian Tang, ShenZhen, PRC. Postal Code=518004
Product description	
Trade Mark:	SWAROVSKI
Product name:	Wireless Charger
Model and/or type reference .:	5502267(SW0042-BK), 5502269(SW0042-WE)
Model Difference	All the same except for the model name and appearance color
Standards:	KDB 680106 D01 RF Exposure Wireless Charging Base App v03 RSS-102 issue 5 and SPR-002 issue 1
Date (s) of performance of tests.	: Jan. 08, 2019 to Jan. 15, 2019
Date of Issue	: Jan. 15, 2019
Test Result	: Pass
Testing Engineer	: Good Bian
	(Gary Qian)
Technical Manager	Edan Hu
	(Eden Hu)
Authorized Signato	ory: Jason Zhori
	(Jason Zhou)

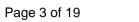




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1. TEST SUMMARY

1.1 TEST PROCEDURES AND RESULTS

DESCRIPTION OF TEST	RESULT
E and H field strength measurements	Compliant

1.2 TEST FACILITY

Test Firm : Shenzhen HUAK Testing Technology Co., Ltd.

Address : 1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road,

Heping Community, Fuhai Street, Bao'an District, Shenzhen,

Guangdong, China

IC Registration No.: 21210 FCC Registration No.: CN1229

Test Firm Registration Number: 616276

1.3 MEASUREMENT UNCERTAINTY

Measurement Uncertainty

Conducted Emission Expanded Uncertainty = 2.23dB, k=2 Radiated emission expanded uncertainty(9kHz-30MHz) = 3.08dB, k=2 Radiated emission expanded uncertainty(30MHz-1000MHz) = 4.42dB, k=2 Radiated emission expanded uncertainty(Above 1GHz) = 4.06dB, k=2



2. GENERAL INFORMATION

2.1. PRODUCT DESCRIPTION

A major technical description of EUT is described as following

Operation Frequency	123.4kHz				
Maximum field strength	53.54dBuV/m(Peak)@3m				
Number of channels	1				
Antenna Designation	Integrated Antenna (Met 15.203 Antenna requirement)				
Hardware Version	Sweda-v9				
Software Version	V1.0				
Power Supply	DC 5V or DC 9V				



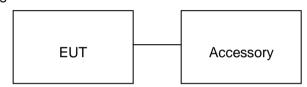


2.2 OPERATION OF EUT DURING TESTING

NO.	TEST MODE DESCRIPTION
1	Wireless charging Mode(Full load)
2	Wireless charging Mode(half load)
3	Wireless charging Mode(Null load)
Note:	he mode 1 was the worst case and only the data of the worst case record in this report.

2.3 DESCRIPTION OF TEST SETUP

Configure:



Item	Equipment	Model No.	ID or Specification	Remark
1	Adapter	RP-PC007	DC 5V3A or DC 9V/2A	Accessory
2	Wireless Load	N/A	10W	Support





3. TEST EQUIPMENT LIST

Description	Description Manufacturer		S/N	Cal. Date	Cal. Due	
Broadband Field	Narda Safety Test	NBM-550	J-0004	June 12, 2018	June 11, 2019	
Meter	Solutions GmbH	INDIVI-550	J-000 4	Julie 12, 2016	Julie 11, 2019	
Drobo EUD	Narda Safety Test		1.0045	luna 40, 2040	luna 44, 2040	
Probe FHP	Solutions GmbH	EHP-50F	J-0015	June 12, 2018	June 11, 2019	





4. RADIO FREQUENCY (RF) EXPOSURE TEST

4.1. LIMITS

FCC:

For devices designed for typical desktop applications, such a wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 15 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 15 cm measured from the center of the probe(s) to the edge of the device and 20 cm measured from the center of the probe(s) to the top of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m.

IC:

Table 2 - Limb Exposure Limit Relaxation

Exposure Condition	Relaxation Factor	Electric Field (V/m r.m.s.)	Magnetic Field (A/m r.m.s.)
Whole Body / Torso / Head	1.0	83	90
Leg	1.5	124.5	135
Arm	2.5	207.5	225
Hand/Foot	5.0	415	450

Note: The values of the electric field and the magnetic field in Table 2 are for indication purposes only and do not supersede the levels specified in RSS-102.

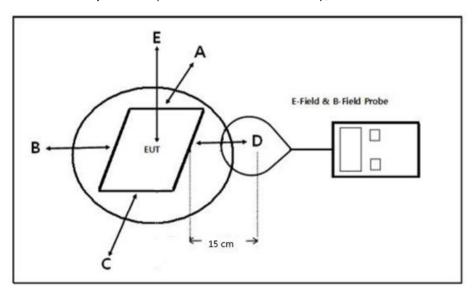


4.2. TEST SETUP

For FCC:

Position A: Front of EUT; Position B: Left of EUT; Position C: back of EUT; Position D: Right of EUT;

Position E: Top of EUT(20 cm measure distance);



For IC:

The compliance distance which is declared by manufacture is 10 cm away from all sides and 10cm from the top of the EUT



4.3. TEST PROCEDURE

FCC:

The EUT was placed on a non-conductive table top and the ancillary equipment (e.g. mobile phone) was placed on the EUT for charging.

Maximum E-field and H-field measurements were tested 15cm from each side of the EUT. For top side the measure distance is 20cm.

Along the side of the EUT to center of E-field probe and H-field probe were positioned at the location to search maximum field strength.

IC:

Passively used table-top devices are those which are placed on a table top; however, the user would not be seated at the table while the device is in use (e.g. cellphone chargers).

Table-top devices shall be installed at the edge of an 80 cm tall table which is constructed of non-metallic material.

Any support equipment used to operate the device shall be placed along the edge with a minimum of 10 cm between each component.

The measurement probe shall be placed at the compliance distance away from the edge of the table.

The compliance distance which is declared by manufacture is 10 cm away from all sides and 10cm from the top of the EUT





4.4. TEST RESULT

FCC:

Test condition: Mode 1 E-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)
123.4kHz	0.16	0.16	0.16	0.16	2.54	614	83

H-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)
123.4kHz	0.18	0.18	0.18	0.18	0.41	1.63	90

Test condition: Mode 2 E-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)
128.7kHz	0.14	0.14	0.14	0.14	1.85	614	83

H-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)
128.7kHz	0.12	0.12	0.12	0.12	0.35	1.63	90



Test condition: Mode 3 E-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)
133.6kHz	0.16	0.16	0.16	0.16	1.48	614	83

H-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)
133.6kHz	0.13	0.13	0.13	0.13	0.27	1.63	90

IC:

Test condition: Mode 1 E-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)
123.4kHz	0.16	0.16	0.16	0.16	4.54	614	83

H-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)
123.4kHz	0.18	0.18	0.18	0.18	0.81	1.63	90





Test condition: Mode 2 E-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)
128.7kHz	0.14	0.14	0.14	0.14	3.54	614	83

H-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)
128.7kHz	0.12	0.12	0.12	0.12	0.66	1.63	90

Test condition: Mode 3 E-field strength test result:

Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)	(V/m)
133.6kHz	0.16	0.16	0.16	0.16	2.45	614	83

H-field strength test result:

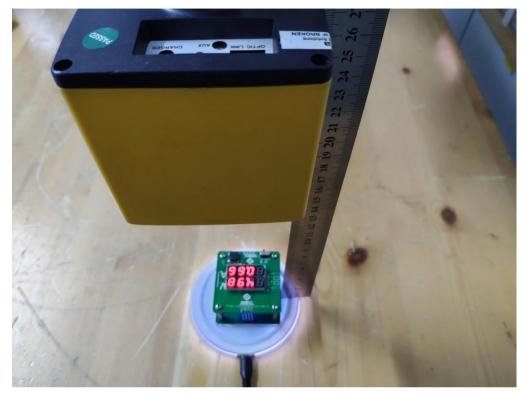
Frequency	Probe	Probe	Probe	Probe	Probe	FCC	IC
Range	Position A	Position B	Position C	Position D	Position E	Limit	Limit
	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)	(A/m)
133.6kHz	0.13	0.13	0.13	0.13	0.52	1.63	90



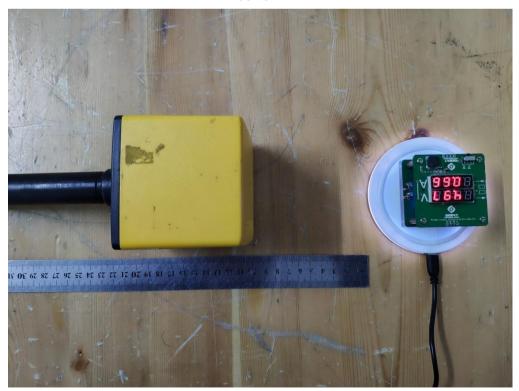
APPENDIX A: PHOTOGRAPHS OF TEST SETUP

FCC

Position E



Position A

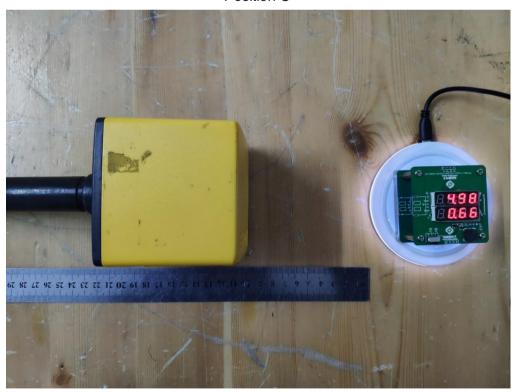




Position B

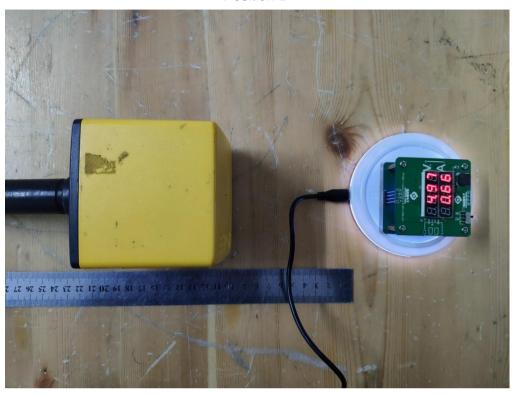


Position C



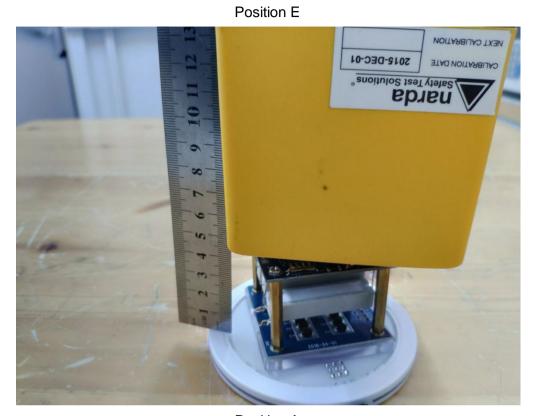


Position D

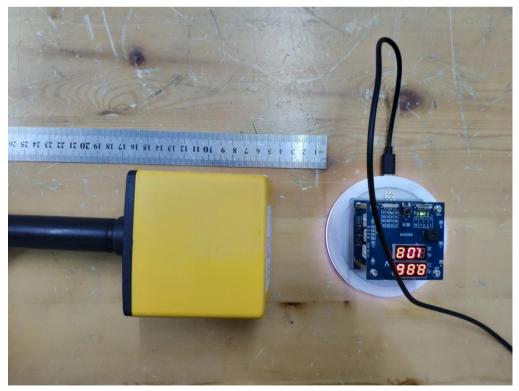




IC



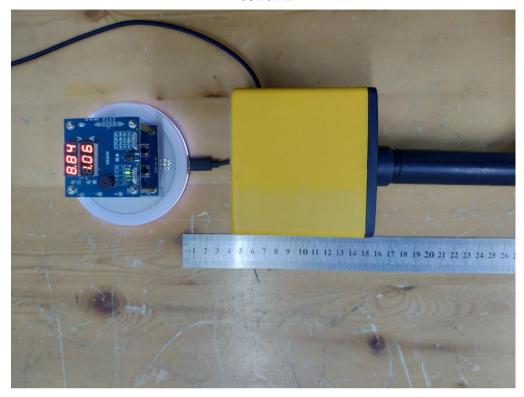
Position A



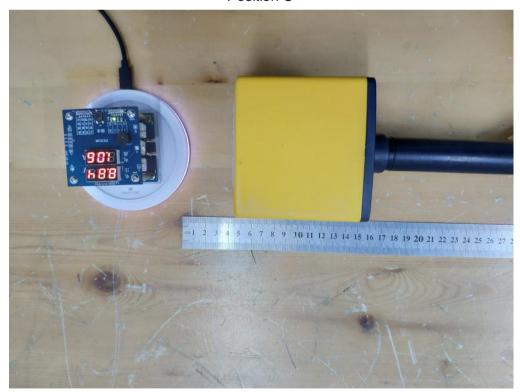


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Position B

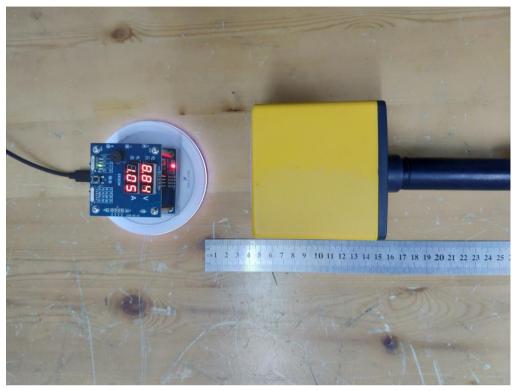


Position C





Position D



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